



# TRUDEVICE Workshop

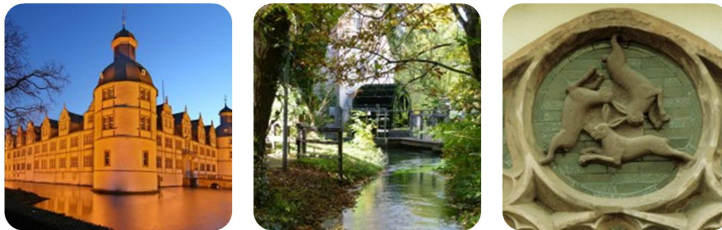
## Test and Fault Tolerance for Secure Devices

### Call for Papers

May 29<sup>th</sup>-30<sup>st</sup>, 2014

Heinz Nixdorf Museums Forum  
Paderborn (Germany)

Co-located with IEEE European Test Symposium



Hardware security is becoming increasingly important for many embedded systems ranging from small RFID tag to satellites orbiting the earth. While secure applications such as public services, communication, control or healthcare keep growing, hardware devices that implement cryptography functions has become the Achille's heel in the last decade. This workshop will specifically target unique challenges of test and fault tolerance of secure devices and the non-trivial relationship between testability of a circuit and its protection against malicious attacks. It will provide an environment for researchers from academic and industrial domains who want to discuss recent findings, theories and on-going work on all aspects of testing and reliability. Program will include invited talks, contributed talks and work in progress.

- Tools and methodologies for testing secure devices
- Secure protocols to access test infrastructures
- Extending security for IEEE system-level test standards
- Fault attacks: models, methods, tools and countermeasures
- Fault-tolerant secure devices

#### Submissions

Perspective authors are invited to submit full contribution (6 pages) or work in progress (2 pages) in PDF format to [trudevice14@lirmm.fr](mailto:trudevice14@lirmm.fr)

#### Paper publication

Accepted papers will be published on the Workshop's website. Every accepted paper must have at least one author registered to the workshop by the time the camera-ready is submitted.

## Committees

### General Co-Chairs:

Giorgio Di Natale, LIRMM (FR)  
Ilia Polian, Univ. of Passau (DE)

### Program Chair:

Marie-Lise Flottes, LIRMM (FR)

### Program Committee:

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B. Rouzeyre, LIRMM (FR)  
M. Tehranipoor, U. Connecticut (USA)



This workshop is co-organized by the COST Action IC1204 (Trustworthy Manufacturing and Utilization of Secure Devices)  
<http://www.trudevice.com/>

**Submission is open to TRUDEVICE members and non-members**

#### Important dates

Submission deadline: March 15, 2014  
Notification of acceptance: April 15, 2014  
Camera ready final version: April 30, 2014

#### For more information

<http://www.trudevice.com>

#### General information

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#### Submissions & Program

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